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# UltraCMOS® RF Digital Step Attenuator, 9 kHz–6 GHz

# Features

- Flexible attenuation steps of 0.25 dB, 0.5 dB and 1 dB up to 31.75 dB
- · Glitch-less attenuation state transitions
- Monotonicity: 0.25 dB up to 4 GHz, 0.5 dB up to 5 GHz and 1 dB up to 6 GHz
- Extended +105 °C operating temperature
- Parallel and Serial programming interfaces with Serial Addressability
- Packaging-32-lead 5 × 5 mm QFN

# Applications

- Test and measurement (T&M)
- General purpose RF attenuator





# **Product Description**

The PE43713 is a 50 $\Omega$ , HaRP<sup>TM</sup> technology-enhanced, 7-bit RF digital step attenuator (DSA) that supports a broad frequency range from 9 kHz to 6 GHz. It features glitch-less attenuation state transitions, supports 1.8V control voltage and includes an extended operating temperature range to +105 °C and optional V<sub>SS\_EXT</sub> bypass mode to improve spurious performance, making this device ideal for test and measurement (T&M).

The PE43713 is a pin-compatible upgraded version of the PE43703. An integrated digital control interface supports both Serial Addressable and Parallel programming of the attenuation, including the capability to program an initial attenuation state at power-up.

The PE43713 covers a 31.75 dB attenuation range in 0.25 dB, 0.5 dB and 1dB steps. It is capable of maintaining 0.25 dB monotonicity through 4 GHz, 0.50 dB monotonicity through 5 GHz and 1 dB monotonicity through 6 GHz. In addition, no external blocking capacitors are required if 0 VDC is present on the RF ports.

The PE43713 is manufactured on Peregrine's UltraCMOS<sup>®</sup> process, a patented variation of silicon-on-insulator (SOI) technology on a sapphire substrate.



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Peregrine's HaRP technology enhancements deliver high linearity and excellent harmonics performance. It is an innovative feature of the UltraCMOS process, offering the performance of GaAs with the economy and integration of conventional CMOS.

# **Optional External V**<sub>ss</sub> **Control**

For proper operation, the  $V_{SS\_EXT}$  control pin must be grounded or tied to the  $V_{SS}$  voltage specified in **Table 2**. When the  $V_{SS\_EXT}$  control pin is grounded, FETs in the switch are biased with an internal negative voltage generator. For applications that require the lowest possible spur performance,  $V_{SS\_EXT}$  can be applied externally to bypass the internal negative voltage generator.

# **Absolute Maximum Ratings**

Exceeding absolute maximum ratings listed in **Table 1** may cause permanent damage. Operation should be restricted to the limits in **Table 2**. Operation between operating range maximum and absolute maximum for extended periods may reduce reliability.

#### **ESD** Precautions

When handling this UltraCMOS device, observe the same precautions as with any other ESD-sensitive devices. Although this device contains circuitry to protect it from damage due to ESD, precautions should be taken to avoid exceeding the rating specified in **Table 1**.

### Latch-up Immunity

Unlike conventional CMOS devices, UltraCMOS devices are immune to latch-up.

#### Table 1 • Absolute Maximum Ratings for PE43713

Parameter/Condition	Min	Мах	Unit
Supply voltage, V <sub>DD</sub>	-0.3	5.5	V
Digital input voltage	-0.3	3.6	V
RF input power, 50Ω 9 kHz–48 MHz >48 MHz–6 GHz		Figure 5 +31	dBm dBm
Storage temperature range	-65	+150	°C
ESD voltage HBM, all pins <sup>(1)</sup>		3000	V
ESD voltage CDM, all pins <sup>(2)</sup>		1000	V
Notes: 1) Human body model (MIL-STD 883 Method 3015).	<u>.</u>		

2) Charged device model (JEDEC JESD22-C101).



# **Recommended Operating Conditions**

**Table 2** lists the recommending operating condition for the PE43713. Devices should not be operated outside the recommended operating conditions listed below.

 Table 2 • Recommended Operating Condition for PE43713

Parameter	Min	Тур	Max	Unit				
Normal mode, V <sub>SS_EXT</sub> = 0V <sup>(1)</sup>		:		+				
Supply voltage, V <sub>DD</sub>	2.3		5.5	V				
Supply current, I <sub>DD</sub>		150	200	μΑ				
Bypass mode, V <sub>SS_EXT</sub> = -3.4V <sup>(2)</sup>				<u>.</u>				
Supply voltage, $V_{DD}$ ( $V_{DD} \ge 3.4V$ see <b>Table 3</b> for full spec compliance)	2.7	3.4	5.5	V				
Supply current, I <sub>DD</sub>		50	80	μΑ				
Negative supply voltage, V <sub>SS_EXT</sub>	-3.6		-2.4	V				
Negative supply current, I <sub>SS</sub>	-40	-16		μΑ				
Normal or bypass mode		1	1					
Digital input high	1.17		3.6	V				
Digital input low	-0.3		0.6	V				
Digital input current			17.5	μΑ				
RF input power, CW <sup>(3)</sup> 9 kHz–48 MHz >48 MHz–6 GHz			Figure 5 +23	dBm dBm				
RF input power, pulsed <sup>(4)</sup> 9 kHz–48 MHz >48 MHz–6 GHz			Figure 5 +28	dBm dBm				
Operating temperature range	-40	+25	+105	°C				
Notes:       1) Normal mode: connect V <sub>SS_EXT</sub> (pin 20) to GND (V <sub>SS_EXT</sub> = 0V) to enable internal negative voltage generator.         2) Bypass mode: use V <sub>SS_EXT</sub> (pin 20) to bypass and disable internal negative voltage generator.         3) 100% duty cycle, all bands, 50Ω.								

4) Pulsed, 5% duty cycle of 4620  $\mu s$  period, 50  $\!\Omega.$ 





# **Electrical Specifications**

**Table 3** provides the PE43713 key electrical specifications at 25 °C, RF1 = RF<sub>IN</sub>, RF2 = RF<sub>OUT</sub> ( $Z_S = Z_L = 50\Omega$ ), unless otherwise specified. Normal mode<sup>(1)</sup> is at V<sub>DD</sub> = 3.3V and V<sub>SS\_EXT</sub> = 0V. Bypass mode<sup>(2)</sup> is at V<sub>DD</sub> = 3.4V and V<sub>SS\_EXT</sub> = -3.4V.

#### Table 3 • PE43713 Electrical Specifications

Parameter	Condition	Frequency	Min	Тур	Мах	Unit					
Operating frequency			9 kHz		6 GHz	As shown					
Attenuation range	0.25 dB step 0.5 dB step 1 dB step			0–31.75 0–31.50 0–31.00		dB dB dB					
Insertion loss		9 kHz–1.0 GHz 1.0–2.2 GHz 2.2–4.0 GHz 4.0–6.0 GHz		1.3 1.6 1.95 2.45	1.5 1.85 2.4 2.8	dB dB dB dB					
	0.25 dB step										
	0–8 dB	9 kHz–2.2 GHz			±(0.20 + 1.5% of attenuation setting)	dB					
	8.25–31.75 dB	9 kHz–2.2 GHz			±(0.20 + 2.0% of attenuation setting)	dB					
	0–31.75 dB	>2.2–3.0 GHz			±(0.15 + 3.0% of attenuation setting)	dB					
Attonuction offer	0–31.75 dB	>3.0–4.0 GHz			±(0.25 + 3.5% of attenuation setting)	dB					
Allendation error	0.5 dB step										
	0–8 dB	9 kHz–2.2 GHz			±(0.20 + 1.5% of attenuation setting)	dB					
	8.5–31.5 dB	9 kHz–2.2 GHz			±(0.20 + 2.0% of attenuation setting)	dB					
	0–31.5 dB	>2.2–3.0 GHz			±(0.15 + 3.0% of attenuation setting)	dB					
	0–31.5 dB	>3.0–5.0 GHz			$\pm(0.25 + 5.0\% \text{ of})$ attenuation setting)	dB					





#### Table 3 • PE43713 Electrical Specifications (Cont.)

Parameter	Condition	Frequency	Min	Тур	Мах	Unit
	1 dB step				·	<u>,</u>
Attenuation error Return loss Relative phase	0–8 dB	9 kHz–2.2 GHz			±(0.20 + 1.5% of attenuation setting)	dB
	9–31 dB	9 kHz–2.2 GHz			±(0.20 + 2.0% of attenuation setting)	dB
Attenuation error	0–31 dB	>2.2–3.0 GHz			±(0.15 + 3.0% of attenuation setting)	dB
	0–31 dB	>3.0–5.0 GHz			±(0.25 + 5.0% of attenuation setting)	dB
	0–31 dB	>5.0–6.0 GHz			±(0.25 + 5.0% of attenuation setting)	dB
Return loss	Input port or output port	9 kHz–4 GHz 4–6 GHz		13 15		dB dB
Relative phase	All states	9 kHz–4 GHz 4–6 GHz		27 42		deg deg
Input 0.1dB compression point <sup>(3)</sup>		48 MHz–6 GHz		31		dBm
Input IP3	Two tones at +18 dBm, 20 MHz spacing	4 GHz 6 GHz		57 56		dBm dBm
RF T <sub>rise</sub> /T <sub>fall</sub>	10%/90% RF			200		ns
Settling time	RF settled to within 0.05 dB of final value			1.6		μs
Switching time	50% CTRL to 90% or 10% RF			275		ns
Attenuation transient (envelope)		2 GHz		0.3		dB

Notes:

1) Normal mode: connect  $V_{SS\_EXT}$  (pin 20) to GND ( $V_{SS\_EXT} = 0V$ ) to enable internal negative voltage generator.

2) Bypass mode: use  $V_{SS\ EXT}$  (pin 20) to bypass and disable internal negative voltage generator.

3) The input 0.1 dB compression point is a linearity figure of merit. Refer to Table 2 for the operating RF input power (50Ω).



### Switching Frequency

The PE43713 has a maximum 25 kHz switching rate in normal mode (pin 20 tied to ground). A faster switching rate is available in bypass mode (pin 20 tied to  $V_{SS\_EXT}$ ). The rate at which the PE43713 can be switched is then limited to the switching time as specified in **Table 3**.

Switching frequency is defined to be the speed at which the DSA can be toggled across attenuation states. Switching time is the time duration between the point the control signal reaches 50% of the final value and the point the output signal reaches within 10% or 90% of its target value.

#### Spur-free Performance

The typical spurious performance of the PE43713 in normal mode is -130 dBm (pin 20 tied to ground). If spur-free performance is desired, the internal negative voltage generator can be disabled by applying a negative voltage to V<sub>SS EXT</sub> (pin 20).

### **Glitch-less Attenuation State Transitions**

The PE43713 features a novel architecture to provide the best-in-class glitch-less transition behavior when changing attenuation states. When RF input power is applied, the output power spikes are greatly reduced ( $\leq 0.3$  dB) during attenuation state changes when comparing to previous generations of DSAs.

# **Truth Tables**

Table 4–Table 6 provide the truth tables for thePE43713.

#### Table 4 • Parallel Truth Table

	Para	Attenuation					
D6	D5	D4	D3	D2	D1	D0	RF1–RF2
L	L	L	L	L	L	L	Reference IL
L	L	L	L	L	L	Н	0.25 dB
L	L	L	L	L	Н	L	0.5 dB
L	L	L	L	Н	L	L	1 dB
L	L	L	Н	L	L	L	2 dB
L	L	н	L	L	L	L	4 dB

#### Table 4 • Parallel Truth Table (Cont.)

	Para	Attenuation					
D6	D5	D4	D3	D2	D1	D0	RF1–RF2
L	Н	L	L	L	L	L	8 dB
Н	L	L	L	L	L	L	16 dB
Н	н	н	Н	н	н	н	31.75 dB

	Addroop							
A7 (MSB)	<b>A</b> 6	A5	<b>A</b> 4	<b>A</b> 3	A2	<b>A</b> 1	A0	Setting
Х	Х	Х	Х	Х	L	L	L	000
Х	Х	Х	Х	Х	L	L	Н	001
Х	Х	Х	Х	Х	L	н	L	010
Х	Х	Х	Х	Х	L	н	н	011
Х	Х	Х	Х	Х	н	L	L	100
Х	Х	Х	Х	Х	н	L	н	101
Х	Х	Х	Х	Х	н	Н	L	110
Х	х	Х	Х	Х	н	н	н	111

Table 6 •	Serial	Attenuation	Word	Truth	Table
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	Attenuation Word						Attenuation	
D7	D6	D5	D4	D3	D2	D1	D0 (LSB)	Setting RF1–RF2
L	L	L	L	L	L	L	L	Reference IL
L	L	L	L	L	L	L	Н	0.25 dB
L	L	L	L	L	L	Н	L	0.5 dB
L	L	L	L	L	н	L	L	1 dB
L	L	L	L	н	L	L	L	2 dB
L	L	L	н	L	L	L	L	4 dB
L	L	н	L	L	L	L	L	8 dB
L	н	L	L	L	L	L	L	16 dB
L	н	н	н	н	н	н	Н	31.75 dB





# Serial Addressable Register Map

Figure 2 provides the Serial Addressable register map for the PE43713.

#### Figure 2 • Serial Addressable Register Map



Address Word

Attenuation Word

The attenuation word is derived directly from the value of the attenuation state. To find the attenuation word, multiply the value of the state by four, then convert to binary.

For example, to program the 18.25 dB state at address 3:

4 × 18.25 = 73 73 → 01001001

Address Word: XXXXX011 Attenuation Word: 01001001 Serial Input: XXXXX01101001001





# **Programming Options**

### Parallel/Serial Selection

Either a Parallel or Serial addressable interface can be used to control the PE43713. The  $\overline{P}/S$  bit provides this selection, with  $\overline{P}/S = LOW$  selecting the Parallel interface and  $\overline{P}/S = HIGH$  selecting the Serial interface.

### Parallel Mode Interface

The Parallel interface consists of seven CMOScompatible control lines that select the desired attenuation state, as shown in **Table 4**.

The Parallel interface timing requirements are defined by **Figure 4** (Parallel Interface Timing Diagram), **Table 9** (Parallel and Direct Interface AC Characteristics) and switching time (**Table 3**).

For Latched Parallel programming, the Latch Enable (LE) should be held LOW while changing attenuation state control values then pulse LE HIGH to LOW (per **Figure 4**) to latch new attenuation state into the device.

For Direct Parallel programming, the LE line should be pulled HIGH. Changing attenuation state control values will change device state to new attenuation. Direct mode is ideal for manual control of the device (using hardwire, switches, or jumpers).

### Serial-Addressable Interface

The Serial-Addressable interface is a 16-bit Serial-In, Parallel-Out shift register buffered by a transparent latch. The 16-bits make up two words comprised of 8bits each. The first word is the Attenuation Word, which controls the state of the DSA. The second word is the Address Word, which is compared to the static (or programmed) logical states of the A0, A1 and A2 digital inputs. If there is an address match, the DSA changes state; otherwise its current state will remain unchanged. **Figure 3** illustrates an example timing diagram for programming a state. It is required that all Parallel control inputs be grounded when the DSA is used in Serial-Addressable mode.

The Serial-Addressable interface is controlled using three CMOS-compatible signals: SI, Clock (CLK) and LE. The SI and CLK inputs allow data to be serially entered into the shift register. Serial data is clocked in LSB first. The shift register must be loaded while LE is held LOW to prevent the attenuator value from changing as data is entered. The LE input should then be toggled HIGH and brought LOW again, latching the new data into the DSA. The Address Word truth table is listed in **Table 5**. The Attenuation Word truth table is listed in **Table 6**. A programming example of the serial register is illustrated in **Figure 2**. The serial timing diagram is illustrated in **Figure 3**.

### **Power-up Control Settings**

The PE43713 will always initialize to the maximum attenuation setting (31.75 dB) on power-up for both the Serial Addressable and Latched Parallel modes of operation and will remain in this setting until the user latches in the next programming word. In Direct Parallel mode, the DSA can be preset to any state within the 31.75 dB range by pre-setting the Parallel control pins prior to power-up. In this mode, there is a 400 µs delay between the time the DSA is poweredup to the time the desired state is set. During this power-up delay, the device attenuates to the maximum attenuation setting (31.75 dB) before defaulting to the user defined state. If the control pins are left floating in this mode during power-up, the device will default to the minimum attenuation setting (insertion loss state).

Dynamic operation between Serial and Parallel programming modes is possible.

If the DSA powers up in Serial mode ( $\overline{P}/S = HIGH$ ), all the Parallel control inputs DI[6:0] must be set to logic LOW. Prior to toggling to Parallel mode, the DSA must be programmed serially to ensure D[7] is set to logic LOW.

If the DSA powers up in either Latched or Direct Parallel mode, all Parallel pins DI[6:0] must be set to logic LOW prior to toggling to Serial Addressable mode ( $\overline{P}/S = HIGH$ ), and held LOW until the DSA has been programmed serially to ensure bit D[7] is set to logic LOW.

The sequencing is only required once on power-up. Once completed, the DSA may be toggled between Serial and Parallel programming modes at will.





#### Figure 3 • Serial Timing Diagram



Figure 4 • Latched Parallel/Direct Parallel Timing Diagram



 Table 7 • Latch and Clock Specifications

Latch Enable	Shift Clock	Function
0	1	Shift register clocked
Î	Х	Contents of shift register transferred to attenuator core



# PE43713 UltraCMOS® RF Digital Step Attenuator



#### Table 8 • Serial Interface AC Characteristics<sup>(\*)</sup>

Parameter/Condition	Min	Мах	Unit
Serial clock frequency, F <sub>CLK</sub>		10	MHz
Serial clock HIGH time, T <sub>CLKH</sub>	30		ns
Serial clock LOW time, T <sub>CLKL</sub>	30		ns
Last Serial clock rising edge setup time to Latch Enable rising edge, T <sub>LESU</sub>	10		ns
Latch Enable minimum pulse width, T <sub>LEPW</sub>	30		ns
Serial data setup time, T <sub>SISU</sub>	10		ns
Serial data hold time, T <sub>SIH</sub>	10		ns
Parallel data setup time, T <sub>DISU</sub>	100		ns
Parallel data hold time, T <sub>DIH</sub>	100		ns
Address setup time, T <sub>ASU</sub>	100		ns
Address hold time, T <sub>AH</sub>	100		ns
Parallel/Serial setup time, T <sub>PSSU</sub>	100		ns
Parallel/Serial hold time, T <sub>PSIH</sub>	100		ns
Digital register delay (internal), T <sub>PD</sub>		10	ns
Note: * $V_{DD}$ = 3.3V or 5.0V, -40 °C, < T <sub>A</sub> < +105 °C, unless otherwise specified.			

#### Table 9 • Parallel and Direct Interface AC Characteristics<sup>(\*)</sup>

Parameter/Condition	Min	Мах	Unit
Latch Enable minimum pulse width, T <sub>LEPW</sub>	30		ns
Parallel data setup time, T <sub>DISU</sub>	100		ns
Parallel data hold time, T <sub>DIH</sub>	100		ns
Parallel/Serial setup time, T <sub>PSSU</sub>	100		ns
Parallel/Serial hold time, T <sub>PSIH</sub>	100		ns
Digital register delay (internal), T <sub>PD</sub>		10	ns
Digital register delay (internal, direct mode only), T <sub>DIPD</sub>		5	ns
Note: * $V_{DD}$ = 3.3V or 5.0V, -40 °C < T <sub>A</sub> < +105 °C, unless otherwise specified.			





#### Figure 5 • Power De-rating Curve, 9 kHz–6 GHz, –40 to +105 °C Ambient, 50Ω





# Typical Performance Data

**Figure 6–Figure 32** show the typical performance data at 25 °C and  $V_{DD}$  = 3.3V, RF1 = RF<sub>IN</sub>, RF2 = RF<sub>OUT</sub> (Z<sub>S</sub> = Z<sub>L</sub> = 50 $\Omega$ ) unless otherwise specified.











Figure 8 • Output Return Loss vs Attenuation Setting



### PE43713 UltraCMOS® RF Digital Step Attenuator







Figure 10 • Output Return Loss for 16 dB Attenuation Setting vs Temperature









Figure 12 • Relative Phase Error for 31.75 dB Attenuation Setting vs Frequency









Figure 14 • Attenuation Error @ 1800 MHz vs Temperature









Figure 16 • Attenuation Error @ 3000 MHz vs Temperature









Figure 18 • IIP3 vs Attenuation Setting









Note: \* Monotonicity is held so long as step attenuation does not cross below -0.25 dB.





### PE43713 UltraCMOS® RF Digital Step Attenuator







Figure 22 • 0.25 dB Attenuation Error vs Frequency









Note: \* Monotonicity is held so long as step attenuation does not cross below -0.5 dB.











Figure 26 • 0.5 dB Attenuation Error vs Frequency









Note: \* Monotonicity is held so long as step attenuation does not cross below -1 dB.











Figure 30 • 1 dB Attenuation Error vs Frequency







Figure 31 • Attenuation Transient (15.75–16 dB), Typical Switching Time = 275 ns

Figure 32 • Attenuation Transient (16–15.75 dB), Typical Switching Time = 275 ns

